



## Product Change Notification - GBNG-31NTMF621

---

**Date:**

14 Feb 2019

**Product Category:**

Interface- Controller Area Network (CAN); Interface- LIN Transceiver

**Affected CPNs:**



**Notification subject:**

CCB 3533 Final Notice: Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN, 16L VDFN and 48L VQFN packages.

**Notification text:**

**PCN Status:**

Final notification.

**PCN Type:**

Manufacturing Change

**Microchip Parts Affected:**

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

**Description of Change:**

Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN, 16L VDFN and 48L VQFN packages.

**Pre Change:**

Tested at MPHL final test site.

**Post Change:**

Tested at MPHL final test site or tested at MTAI final test site.

**Pre and Post Change Summary:**

	Pre Change	Post Change	
Final Test Site	Microchip Technology Operations (Philippines) Corporation (MPHL)	Microchip Technology Operations (Philippines) Corporation (MPHL)	Microchip Technology Thailand (HQ) (MTAI)

**Impacts to Data Sheet:**

None

**Change Impact:**

None

**Reason for Change:**

To improve manufacturability by qualifying MTAI as an additional final test site.

**Change Implementation Status:**

In Progress

**Estimated First Ship Date:**

Estimated First Ship Date (EFSD) are identified for each catalog part numbers (CPN) listed in the attached parts list. This can be found in the attachments field below labeled as PCN\_#\_Affected\_CPN.



NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

**Time Table Summary:**

Workweek	September 2018				-->	February 2019					March 2019			
	36	37	38	39		05	06	07	08	09	10	11	12	13
Initial PCN Issue Date		X												
Qual Report Availability							X							
Final PCN Issue Date							X							
Estimated Implementation Date											As listed in the attached parts list			

**Method to Identify Change:**

Traceability code

**Qualification Report:**

Please open the attachments included with this PCN labeled as PCN\_#\_Qual Report.

**Revision History:**

**September 13, 2018:** Issued initial notification.

**February 14, 2019:** Issued final notification. Attached the qualification report. Revised the affected parts list. Added 48L VQFN package in notification subject and description of change based on updated scope. Provided estimated first ship date (EFSD) for each CPN listed in the attached parts list.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

**Attachment(s):**

- [PCN\\_GBNG-31NTMF621\\_Qual\\_Report.pdf](#)
- [PCN\\_GBNG-31NTMF621\\_Affected\\_CPN.pdf](#)
- [PCN\\_GBNG-31NTMF621\\_Affected\\_CPN.xlsx](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

**Terms and Conditions:**

If you wish to [receive Microchip PCNs via email](#) please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to [change your PCN profile, including opt out](#), please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.



## **QUALIFICATION REPORT SUMMARY**

**PCN #: GBNG-31NTMF621**

**Date**  
**February 01, 2019**

**Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN, 16L VDFN and 48L VQFN packages.**

**Purpose: Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN, 16L VDFN and 48L VQFN packages.**

**CCB No.: 3533**

Test / Evaluation	Test Conditions / Parameters	Result
<b>Datalog / Bin Comparison</b>	<ul style="list-style-type: none"> <li>• Compare test numbers, test names, test limit, test sequence, bin assignments &amp; pass/fail results</li> <li>• Accept if all match or justify the differences</li> </ul>	PASSED
<b>Test stability verification</b>	<ul style="list-style-type: none"> <li>• 50 loops on single TD (60 Sites) with STDF</li> <li>• Accept on Cp &gt; 1.67 or justify/waive parameters if needed</li> </ul>	PASSED
<b>Parametric Correlation</b>	<ul style="list-style-type: none"> <li>• Perform GR&amp;R. Site 1: SPEA vs LTX</li> <li>• Accept on GR&amp;R &lt; 10% or justify/waive parameters if needed</li> </ul>	PASSED
<b>Site to site comparison</b>	<ul style="list-style-type: none"> <li>• Perform test capability and compare (TCC). SPEA_Site1 vs SPEA_SiteX.</li> <li>• Accept R&amp;R &lt; 10% and Cpk &gt; 1.67 or justify/waive parameters if needed</li> </ul>	PASSED
<b>Unit to unit parametric correlation</b>	<ul style="list-style-type: none"> <li>• Run one full strip or &gt;50 units correlation on strip, serialize, then run in singulated.</li> <li>• Accept if all match or justify the differences (including reject correlation)</li> </ul>	PASSED
<b>Peak Voltage</b>	<ul style="list-style-type: none"> <li>• Check voltage peaks for each device pin at SPEA (minimum of 2 sites).</li> <li>• No voltage peaks &gt; Maximum Ratings from datasheet.</li> </ul>	PASSED
<b>Lot Correlation</b>	<p><u>3 Lots Correlation /~5k per lot</u></p> <ul style="list-style-type: none"> <li>• 100% test on Strip with SPEA tester, send back to assembly for singulation, then 100% test on singulated tester.</li> <li>• Accept <math>\pm 0.1\%</math> yield difference, Sigma Ratio &lt; 1.5 and Delta Average &lt; 10%. Reject should be matched or justify the differences.</li> </ul>	PASSED

CCB 3533 Final Notice: Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN, 16L VDFN and 48L VQFN packages.

Affected Catalog Part Numbers (CPN)

PCN_GBNG-31NTMF621	
CATALOG_PART_NBR	Estimated First Ship Date (EFS)
ATA6560-GAQW	May 2019
ATA6560-GAQW-N	May 2019
ATA6561-GAQW	July 2019
ATA6561-GAQW-N	July 2019
ATA6562-GAQW0	August 2019
ATA6562-GAQW1	August 2019
ATA6563-GAQW0	September 2019
ATA6563-GAQW1	September 2019
ATA6564-GAQW0	October 2019
ATA6564-GAQW1	October 2019
ATA6565-GCQW0	March 2020
ATA6566-GAQW0	February 2020
ATA6566-GAQW1	February 2020
ATA6566-GBQW0	February 2020
ATA6570-GNQW1	September 2019
ATA6562-GBQW0	October 2019
ATA6562-GBQW1	October 2019
ATA6563-GBQW0	October 2019
ATA6563-GBQW1	October 2019
ATA6564-GBQW0	October 2019
ATA6564-GBQW1	October 2019
ATA663331-GDQW	April 2020
ATA6560-GBQW	September 2019
ATA6560-GBQW-N	September 2019
ATA6561-GBQW	September 2019
ATA6561-GBQW-N	September 2019
ATA6566-GBQW1	October 2019
ATA6565-GCQW1	October 2019
ATA6670-FFQW-1	September 2019
ATA663354-GDQW	March 2020
ATA663431-GDQW	September 2019
ATA663454-GDQW	September 2019
ATSAMHA1G14A-MBT	August 2019
ATSAMHA1G15A-MBT	August 2019
ATSAMHA1G16A-MBT	August 2019